

Search Notes

Application/Control No.

10/667,663

Examiner

Thien M. Le

Applicant(s)/Patent under
Reexamination

SHIRAISHI ET AL.

Art Unit

2876

SEARCHED

Class	Subclass	Date	Examiner
235	492		
	375		
	441		
	493		
	486		
	487		
365	185,11		
	185,33		
707	100		
	200		
	2	6/22/2005	LTM
updated		2/1/2006	LTM

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
235	492	2/3/2006	LTM